



ALPHA & OMEGA
SEMICONDUCTOR

AOUS66616
60V N-Channel AlphaSGT™

General Description

- Trench Power MOSFET - AlphaSGT™ technology
- Low $R_{DS(ON)}$
- Excellent Gate Charge $\times R_{DS(ON)}$ Product (FOM)
- RoHS and Halogen-Free Compliant

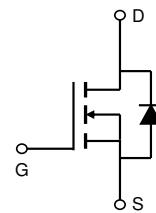
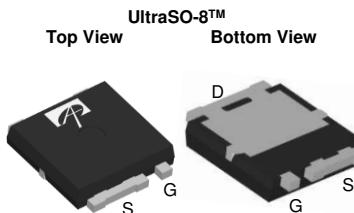
Product Summary

V_{DS}	60V
I_D (at $V_{GS}=10V$)	92A
$R_{DS(ON)}$ (at $V_{GS}=10V$)	< 3.3mΩ
$R_{DS(ON)}$ (at $V_{GS}=6V$)	< 4.7mΩ

Applications

- Synchronous Rectification in DC/DC and AC/DC Converters
- Industrial and Motor Drive applications

100% UIS Tested
100% R_g Tested



Orderable Part Number	Package Type	Form	Minimum Order Quantity
AOUS66616	Ultra SO8	Tape & Reel	3000

Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	60	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current ^G	I_D	92	A
$T_C=100^\circ\text{C}$		80	
Pulsed Drain Current ^C	I_{DM}	330	
Continuous Drain Current	I_{DSM}	33	A
$T_A=70^\circ\text{C}$		26	
Avalanche Current ^C	I_{AS}	35	A
Avalanche energy $L=0.3\text{mH}$ ^C	E_{AS}	184	mJ
Power Dissipation ^B	P_D	92.5	W
$T_C=100^\circ\text{C}$		37	
Power Dissipation ^A	P_{DSM}	6.2	W
$T_A=70^\circ\text{C}$		4.0	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A	$R_{\theta JA}$	15	20	°C/W
Maximum Junction-to-Ambient ^{A,D}		40	50	°C/W
Maximum Junction-to-Case	$R_{\theta JC}$	1.1	1.35	°C/W

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	60			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=60\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			1 5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 20\text{V}$			± 100	nA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	2.4	2.9	3.4	V
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=20\text{A}$ $T_J=125^\circ\text{C}$		2.6	3.3	$\text{m}\Omega$
		$V_{GS}=6\text{V}, I_D=20\text{A}$		4.1	5.2	$\text{m}\Omega$
				3.5	4.7	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=5\text{V}, I_D=20\text{A}$		100		S
V_{SD}	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.7	1	V
I_S	Maximum Body-Diode Continuous Current ^G				92	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=30\text{V}, f=1\text{MHz}$		2870		pF
C_{oss}	Output Capacitance			940		pF
C_{rss}	Reverse Transfer Capacitance			38		pF
R_g	Gate resistance	$f=1\text{MHz}$	0.6	1.25	1.9	Ω
SWITCHING PARAMETERS						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=30\text{V}, I_D=20\text{A}$		42.5	60	nC
Q_{gs}	Gate Source Charge			12		nC
Q_{gd}	Gate Drain Charge			10		nC
Q_{oss}	Output Charge	$V_{GS}=0\text{V}, V_{DS}=30\text{V}$		54		nC
$t_{\text{D(on)}}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=30\text{V}, R_L=1.5\Omega, R_{\text{GEN}}=3\Omega$		14.5		ns
t_r	Turn-On Rise Time			15.5		ns
$t_{\text{D(off)}}$	Turn-Off Delay Time			33		ns
t_f	Turn-Off Fall Time			12.5		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=20\text{A}, \text{di}/\text{dt}=500\text{A}/\mu\text{s}$		26		ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=20\text{A}, \text{di}/\text{dt}=500\text{A}/\mu\text{s}$		87		nC

A. The value of R_{OJA} is measured with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{ C}$. The Power dissipation P_{DSM} is based on $R_{\text{OJA}} \leq 10\text{s}$ and the maximum allowed junction temperature of 150° C . The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=150^\circ\text{ C}$, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Single pulse width limited by junction temperature $T_{J(\text{MAX})}=150^\circ\text{ C}$.

D. The R_{OJA} is the sum of the thermal impedance from junction to case R_{OJC} and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using $<300\mu\text{s}$ pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(\text{MAX})}=150^\circ\text{ C}$. The SOA curve provides a single pulse rating.

G. The maximum current rating is package limited.

H. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{ C}$.

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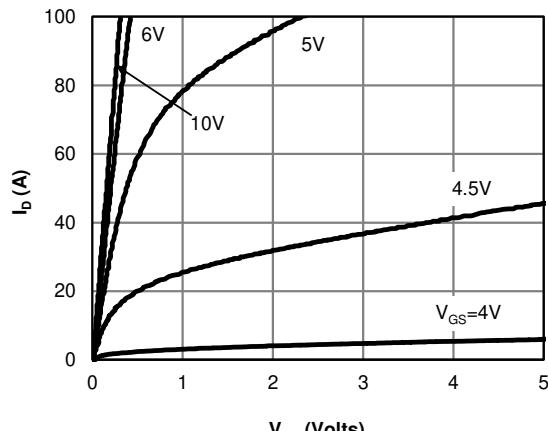
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS


Figure 1: On-Region Characteristics (Note E)

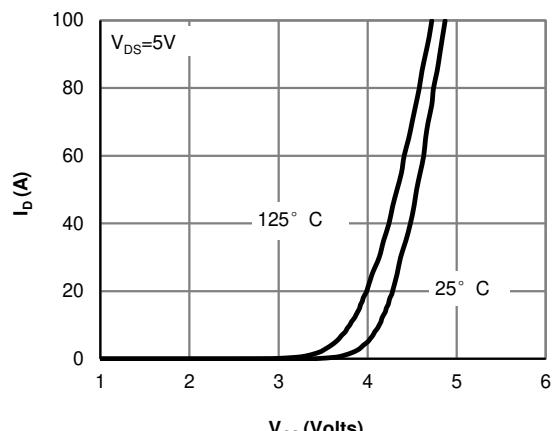


Figure 2: Transfer Characteristics (Note E)

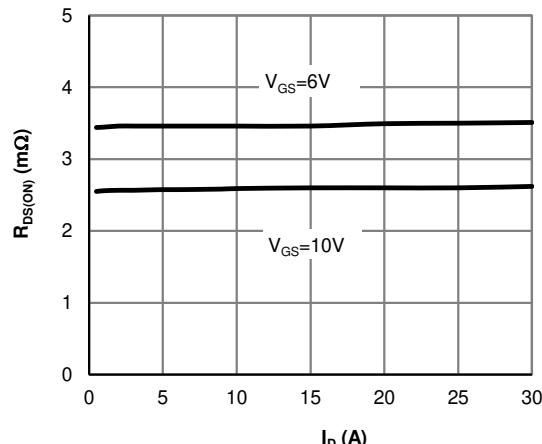


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

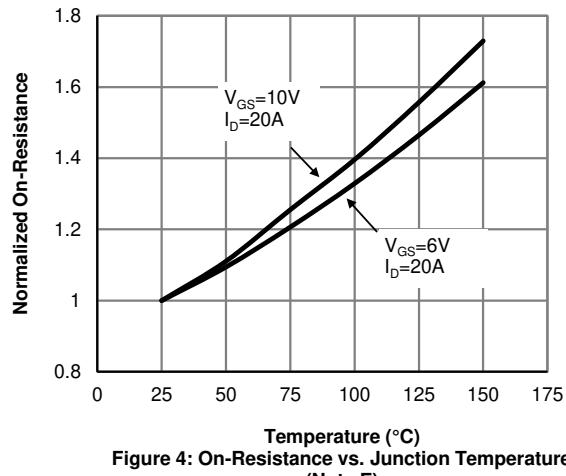


Figure 4: On-Resistance vs. Junction Temperature (Note E)

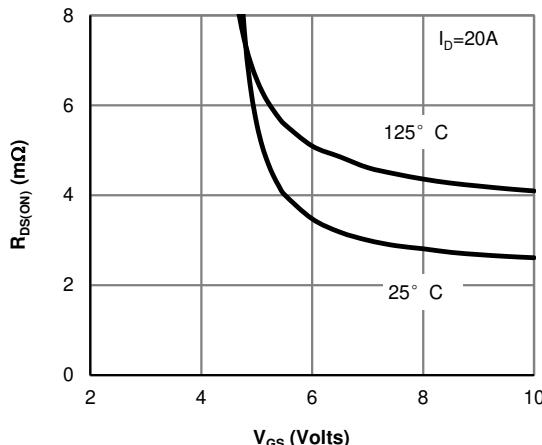


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

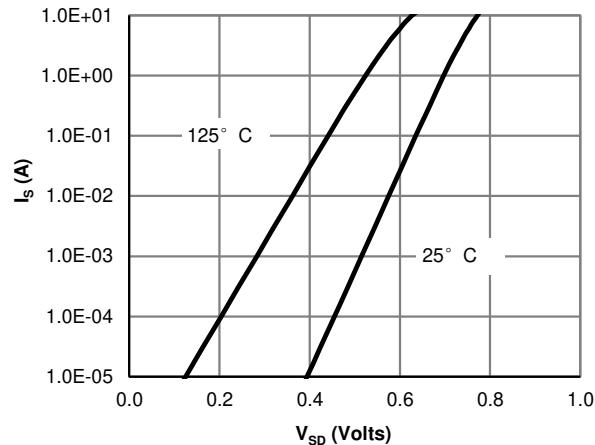
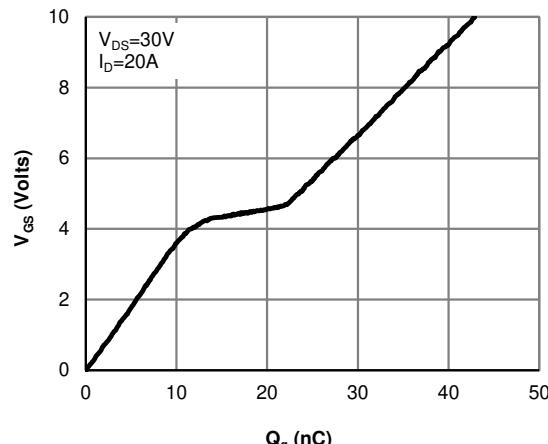
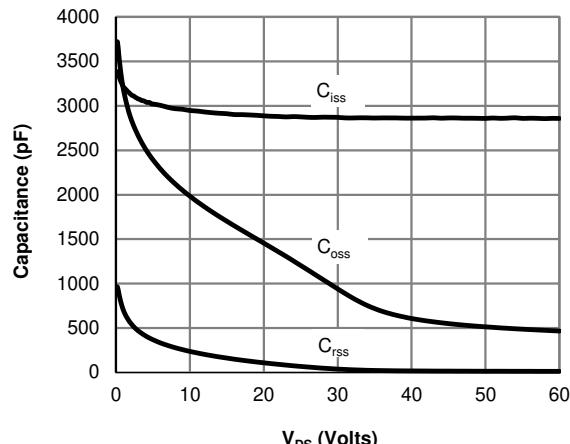
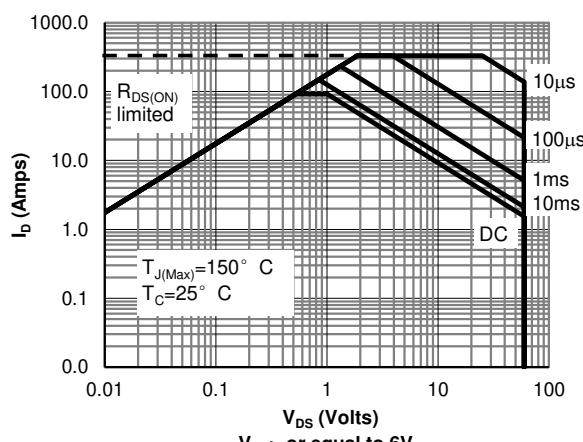
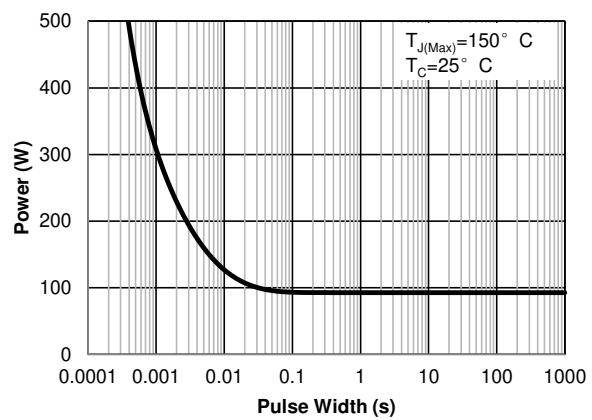
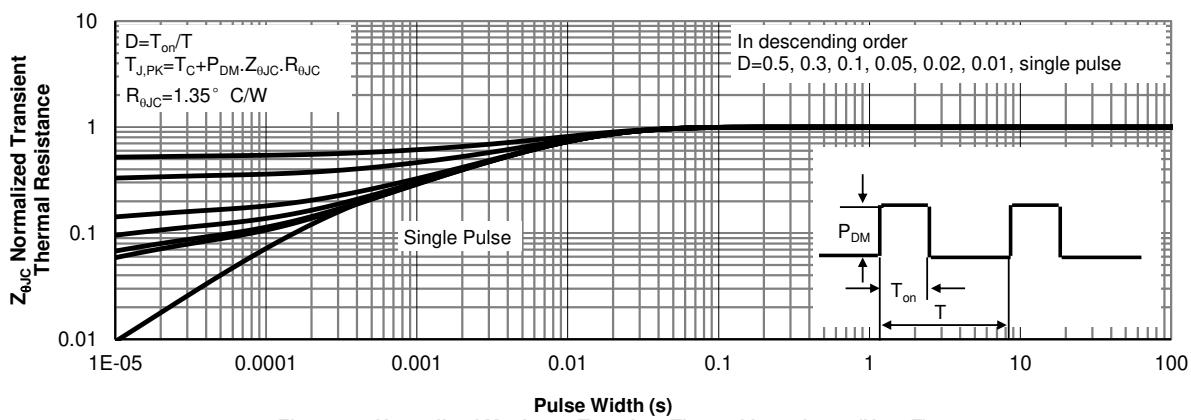


Figure 6: Body-Diode Characteristics (Note E)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 7: Gate-Charge Characteristics

Figure 8: Capacitance Characteristics

Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

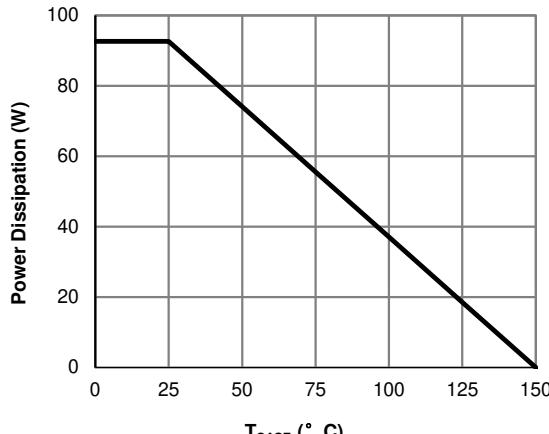
TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS


Figure 12: Power De-rating (Note F)

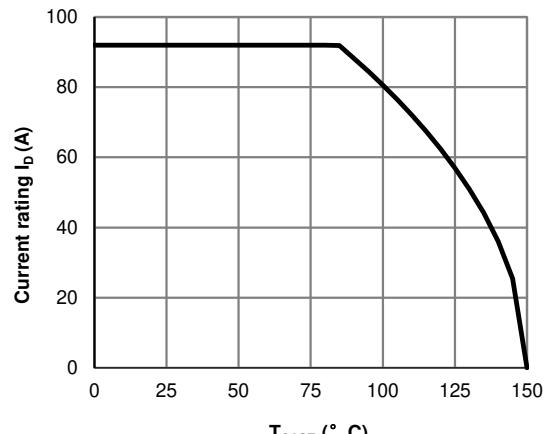


Figure 13: Current De-rating (Note F)

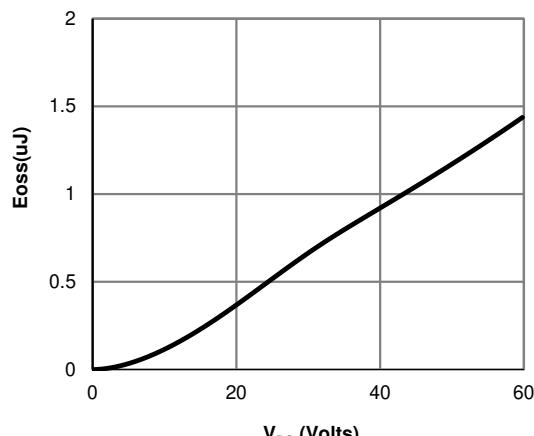


Figure 14: Coss stored Energy

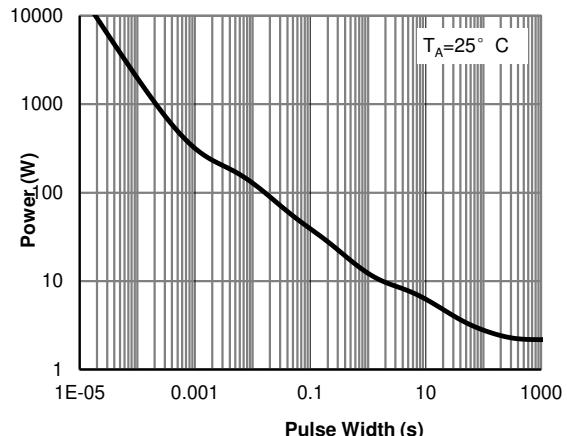


Figure 15: Single Pulse Power Rating Junction-to-Ambient (Note H)

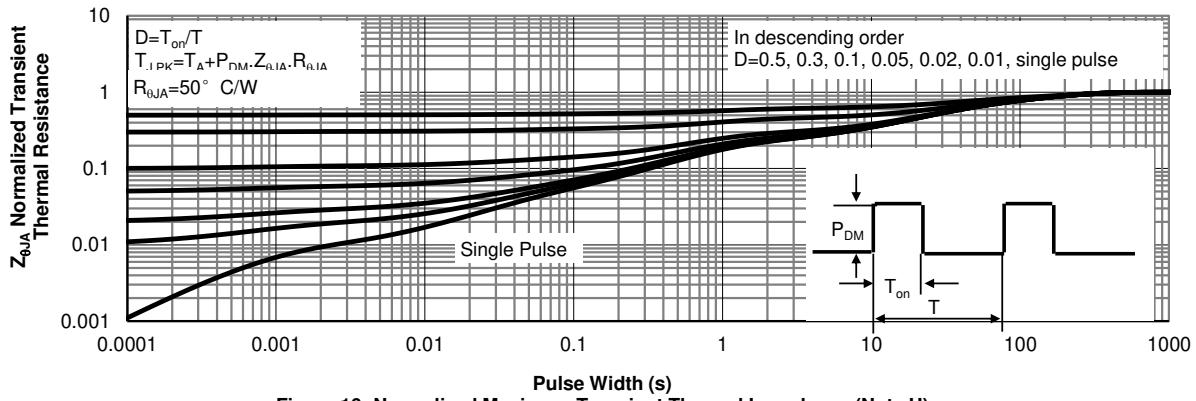


Figure 16: Normalized Maximum Transient Thermal Impedance (Note H)

Figure A: Gate Charge Test Circuit & Waveforms

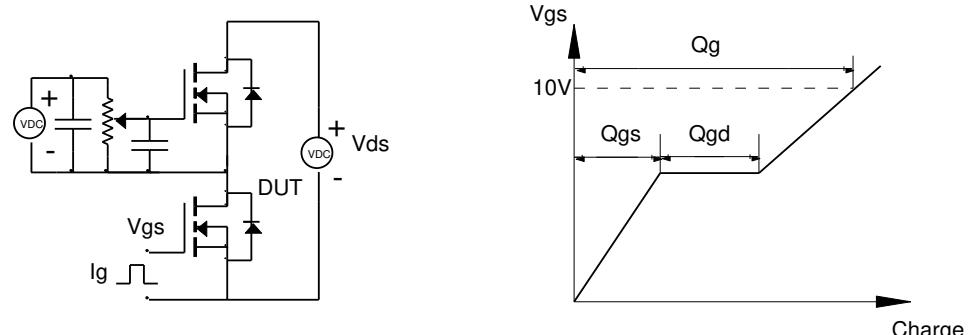


Figure B: Resistive Switching Test Circuit & Waveforms

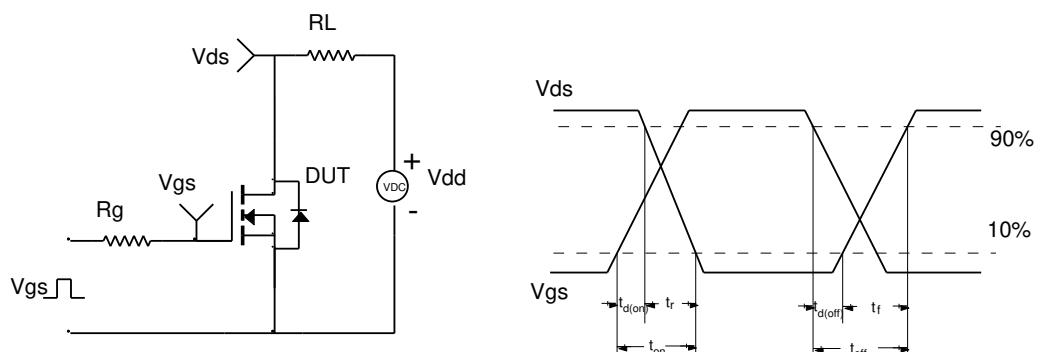


Figure C: Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

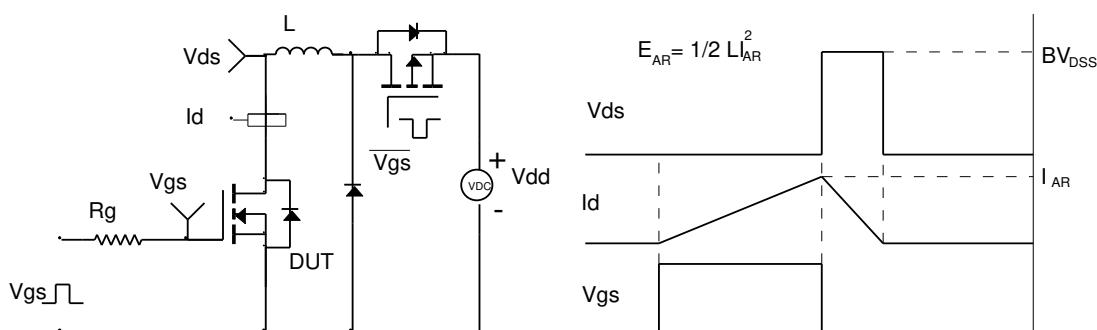


Figure D: Diode Recovery Test Circuit & Waveforms

